SLOVENSKI STANDARD
SIST EN 61967-2:2006

01-februar-2006

Integrirana vezja – Meritve elektromagnetnega oddajanja v območju od 150 kHz do 1 GHz – 2. del: Meritve sevanih oddajanj – Metoda s celico TEM in s širokopasovno celico TEM (IEC 61967-2:2005)

Integrated circuits - Measurement of electromagnetic emissions, 150 kHz to 1 GHz -- Part 2: Measurement of radiated emissions - TEM cell and wideband TEM cell method

Integrierte Schaltungen - Messung von elektromagnetischen Aussendungen im Frequenzbereich von 150 kHz bis 1 GHz -- Teil 2: Messung der abgestrahlten Aussendungen - TEM-Zellen- und Breitband-TEM-Zellenverfahren

Circuits intégrés - Mesure des émissions électromagnétiques, 150 kHz à 1 GHz -- Partie 2: Mesure des émissions rayonnées - Méthode de cellule TEM et cellule TEM à large bande

Ta slovenski standard je istoveten z: **EN 61967-2:2005**

ICS:

31.200	Integrirana vezja, mikroelektronika	Integrated circuits. Microelectronics

SIST EN 61967-2:2006 **en**

EUROPEAN STANDARD **EN 61967-2**

NORME EUROPÉENNE

EUROPÄISCHE NORM October 2005

ICS 31.080.99

English version

Integrated circuits - Measurement of electromagnetic emissions, 150 kHz to 1 GHz Part 2: Measurement of radiated emissions - TEM cell and wideband TEM cell method

(IEC 61967-2:2005)

Circuits intégrés - Mesure des émissions électromagnétiques, 150 kHz à 1 GHz Partie 2: Mesure des émissions rayonnées - Méthode de cellule TEM et cellule TEM à large bande (CEI 61967-2:2005)

Integrierte Schaltungen - Messung von elektromagnetischen Aussendungen im Frequenzbereich von 150 kHz bis 1 GHz Teil 2: Messung der abgestrahlten Aussendungen - TEM-Zellen- und Breitband-TEM-Zellenverfahren (IEC 61967-2:2005)

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This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the Central Secretariat has the same status as the official versions.

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CENELEC

European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

Central Secretariat: rue de Stassart 35, B - 1050 Brussels

Ref. No. EN 61967-2:2005 E

Foreword

The text of document 47A/722/FDIS, future edition 1 of IEC 61967-2, prepared by SC 47A, Integrated circuits, of IEC TC 47, Semiconductor devices, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 61967-2 on 2005-09-01.

This part of EN 61967 is to be read in conjunction with EN 61967-1.

The following dates were fixed:

– latest date by which the EN has to be implemented at national level by publication of an identical national standard or by endorsement	(dop)	2006-07-01
– latest date by which the national standards conflicting with the EN have to be withdrawn	(dow)	2008-09-01

Annex ZA has been added by CENELEC.

Endorsement notice

The text of the International Standard IEC 61967-2:2005 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following notes have to be added for the standards indicated:

IEC 61000-4-3	NOTE	Harmonized as EN 61000-4-3:1996 (modified).
IEC 61000-4-20	NOTE	Harmonized as EN 61000-4-20:2003 (not modified).
CISPR 16-1-1	NOTE	Harmonized as EN 55016-1-1:2004 (not modified).
CISPR 16-1-2	NOTE	Harmonized as EN 55016-1-2:2004 (not modified).
CISPR 16-1-4	NOTE	Harmonized as EN 55016-1-4:2004 (not modified).
CISPR 16-1-5	NOTE	Harmonized as EN 55016-1-5:2004 (not modified).
CISPR 16-2-1	NOTE	Harmonized as EN 55016-2-1:2004 (not modified).
CISPR 16-2-2	NOTE	Harmonized as EN 55016-2-2:2004 (not modified).
CISPR 16-2-3	NOTE	Harmonized as EN 55016-2-3:2004 (not modified).
CISPR 16-2-4	NOTE	Harmonized as EN 55016-2-4:2004 (not modified).

Annex ZA
(normative)

Normative references to international publications with their corresponding European publications

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE Where an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

Publication	Year	Title	EN/HD	Year
IEC 60050-131	2002	International Electrotechnical Vocabulary Part 131: Circuit theory	-	-
IEC 60050-161	1990	Chapter 161: Electromagnetic compatibility	-	-
IEC 61967-1	- [1)]	Integrated circuits - Measurement of electromagnetic emissions, 150 kHz to 1 GHz Part 1: General conditions and definitions	EN 61967-1	2002 [2)]

[1)] Undated reference.

[2)] Valid edition at date of issue.

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Première édition
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2005-09

Circuits intégrés – Mesure des émissions électromagnétiques, 150 kHz à 1 GHz –

Partie 2: Mesure des émissions rayonnées – Méthode de cellule TEM et cellule TEM à large bande

Integrated circuits – Measurement of electromagnetic emissions, 150 kHz to 1 GHz –

Part 2: Measurement of radiated emissions – TEM cell and wideband TEM cell method

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International Electrotechnical Commission
Международная Электротехническая Комиссия

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INTEGRATED CIRCUITS –
MEASUREMENT OF ELECTROMAGNETIC EMISSIONS,
150 kHz TO 1 GHz –

Part 2: Measurement of radiated emissions –
TEM cell and wideband TEM cell method

FOREWORD

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International Standard IEC 61967-2 has been prepared by subcommittee 47A: Integrated circuits, of IEC technical committee 47: Semiconductor devices.

The text of this standard is based on the following documents:

FDIS	Report on voting
47A/722/FDIS	47A/729/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

This part of IEC 61967 is to be read in conjunction with IEC 61967-1.

IEC 61967 consists of the following parts, under the general title *Integrated circuits – Measurement of electromagnetic emissions, 150 kHz to 1 GHz:*

Part 1: General conditions and definitions

Part 2: Measurement of radiated emissions – TEM cell and wideband TEM cell method

Part 3: Measurement of radiated emissions – Surface scan method

Part 4: Measurement of conducted emissions – 1 Ω/150 Ω direct coupling method

Part 5: Measurement of conducted emissions – Workbench Faraday Cage method

Part 6: Measurement of conducted emissions – Magnetic probe method

The committee has decided that the contents of this publication will remain unchanged until the maintenance result date indicated on the IEC web site under "http://webstore.iec.ch" in the data related to the specific publication. At this date, the publication will be

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- withdrawn,
- replaced by a revised edition, or
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